SLOVENSKI STANDARD

SIST EN 60269-4:1998/A1:1998

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april 1998

Low-voltage fuses - Part 4: Supplementary requirements for fuse-links for the protection of semiconductor devices - Amendment A1 (IEC 60269-4:1986/A1:1995)

ICS 29.120.50

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Descriptors: Low-voltage fuses, fuse-links, protection of semiconductor devices, supplementary requirements, characteristics, markings, tests

English version

Low-voltage fuses
Part 4: Supplementary requirements for fuse-links for the protection of semiconductor devices
(IEC 269-4:1986/A1:1995)

Fusibles basse tension
Partie 4: Prescriptions supplémentaires concernant les éléments de remplacement utilisés pour la protection des dispositifs à semi-conducteurs
(CEI 269-4:1986/A1:1995)

Niederspannungssicherungen
Teil 4: Zusätzliche Anforderungen an Sicherungseinsätze zum Schutz von Halbleiter-Bauelementen
(IEC 269-4:1986/A1:1995)

This amendment A1 modifies the European Standard EN 60269-4:1996; it was approved by CENELEC on 1997-03-11. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this amendment the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This amendment exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, Netherlands, Norway, Portugal, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of amendment 1:1995 to the International Standard IEC 269-4:1986, prepared by SC 32B, Low-voltage fuses, of IEC TC 32, Fuses, was submitted to the Unique Acceptance Procedure and was approved by CENELEC as amendment A1 to EN 60269-4:1996 on 1997-03-11 without any modification.

The following dates were fixed:

- latest date by which the amendment has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 1997-12-01
- latest date by which the national standards conflicting with the amendment have to be withdrawn (dow) 1997-12-01

For products which have complied with EN 60269-4:1996 before 1997-12-01, as shown by the manufacturer or by a certification body, this previous standard may continue to apply for production until 2002-12-01.

Endorsement notice

The text of amendment 1:1995 to the International Standard IEC 269-4:1986 was approved by CENELEC as an amendment to the European Standard without any modification.

NORME INTERNATIONALE
INTERNATIONAL STANDARD

CEI
IEC
269-4

1986

AMENDEMENT 1
AMENDMENT 1

1995-12

Amendement 1

Fusibles basse tension –

Partie 4:
Prescriptions supplémentaires concernant les éléments de remplacement utilisés pour la protection des dispositifs à semiconducteurs

Amendment 1

Low-voltage fuses –

Part 4:
Supplementary requirements for fuse-links for the protection of semiconductor devices

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IEC
Commission Electrotechnique Internationale
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Международная Электротехническая Комиссия

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FOREWORD

This amendment has been prepared by sub-committee 32B: Low-voltage fuses, of IEC technical committee 32: Fuses.

The text of this amendment is based on the following documents:

FDIS	Report on voting
32B/247/FDIS	32B/256/RVD

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

Page 11

2.2.10 *Utilization category (of a fuse-link)*

Delete this subclause.

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Add the following new subclause after subclause 5.6.4.2.

5.7.1 *Breaking range and utilization category*

The first letter shall indicate the breaking range. "a" designates fuse-links with partial range breaking capacity (see 7.4).

The second letter, "R", shall indicate the utilization category for fuse-links complying with this standard for the protection of semiconductor devices.

Thus "aR" indicates fuse-links with a partial range breaking capacity for the protection of semiconductor devices.

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7.5 *Breaking capacity*

Replace the last sentence of the subclause by the following sentence:

– for d.c., at time constants not greater than the value appropriate to the value of the prospective current (see table XIIB).

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8.4.3.2 *Verification of rated current*

Add after the title:

(see subclause A3.3)

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8.4.3.6 *Operation of indicating devices and strikers, if any*

Replace the text of the subclause by the following text:

The correct operation of indicating devices is verified in combination with the verification of breaking capacity (see 8.5.5).

For verifying the operation of strikers, if any, an additional test sample shall be tested:

- at a current of I_{2a} (see table XIIA), and
- at a recovery voltage of 20 V.

The value of the recovery voltage may be exceeded by 10 %.

The striker shall operate during all tests.

However, if during one of these tests the indicating device or striker fails, the test shall not be considered negative on this account, if the manufacturer can furnish evidence that such failure is not typical of the fuse type, but it is due to a fault on the individual tested sample. If such a failure occurs, then twice the number of samples shall be tested for the particular test duty, without further failure.

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TABLE XIIB – *Values for breaking capacity tests on d.c. fuses*

Amend the part of the table relating to the time constant.

Time constant ***	Where prospective test current is greater than 20 kA: 10 ms to 12 ms Where prospective test current *I* is equal or less than 20 kA: 0,5 $(I)^{0.3}$ ms with a tolerance of $^{+20}_{0}$ % **

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Notes for figure 2a.

Replace note 7 by the following text:

7. Contact surface to be plated.